

Optical interferometry – a gentle introduction

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Motivation

- A – Uninterested: here for the holiday.
- B – Might be interested but sceptical: prove it to me!
- C – Possibly interested: need to learn more.
- D – Interested: want to understand how I can use this.
- E – I know this is exciting: looking to raise my game.

Outline

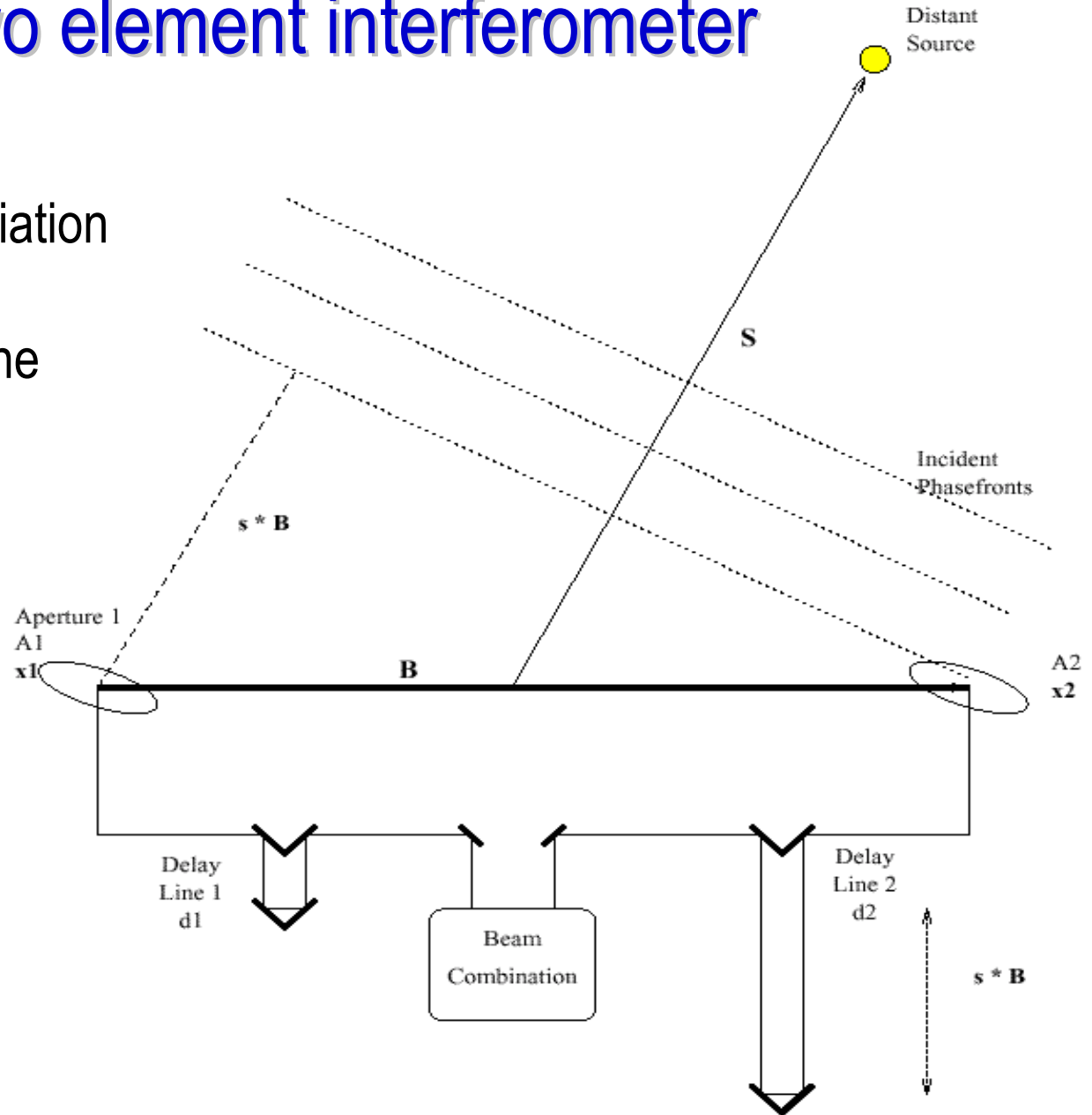
- Preamble
- A simple interferometer
- Fringe parameters
- Information about the source
- Typical visibility functions
- Putting it all together
- Summary

Preamble

- Learning interferometry is like learning to surf:
 - You have to want to do it.
 - You start in the shallows.
 - Having an expensive surf-board doesn't help.
 - You don't have to know how to make surf-boards.
 - Knowing how to surf won't help you escape a charging tiger.
- This is a school:
 - I will assume nothing.
 - You should assume nothing – don't guess.
 - Ask questions.
 - If you don't understand ask the teachers.
- I am not trying to sell you a surf board.

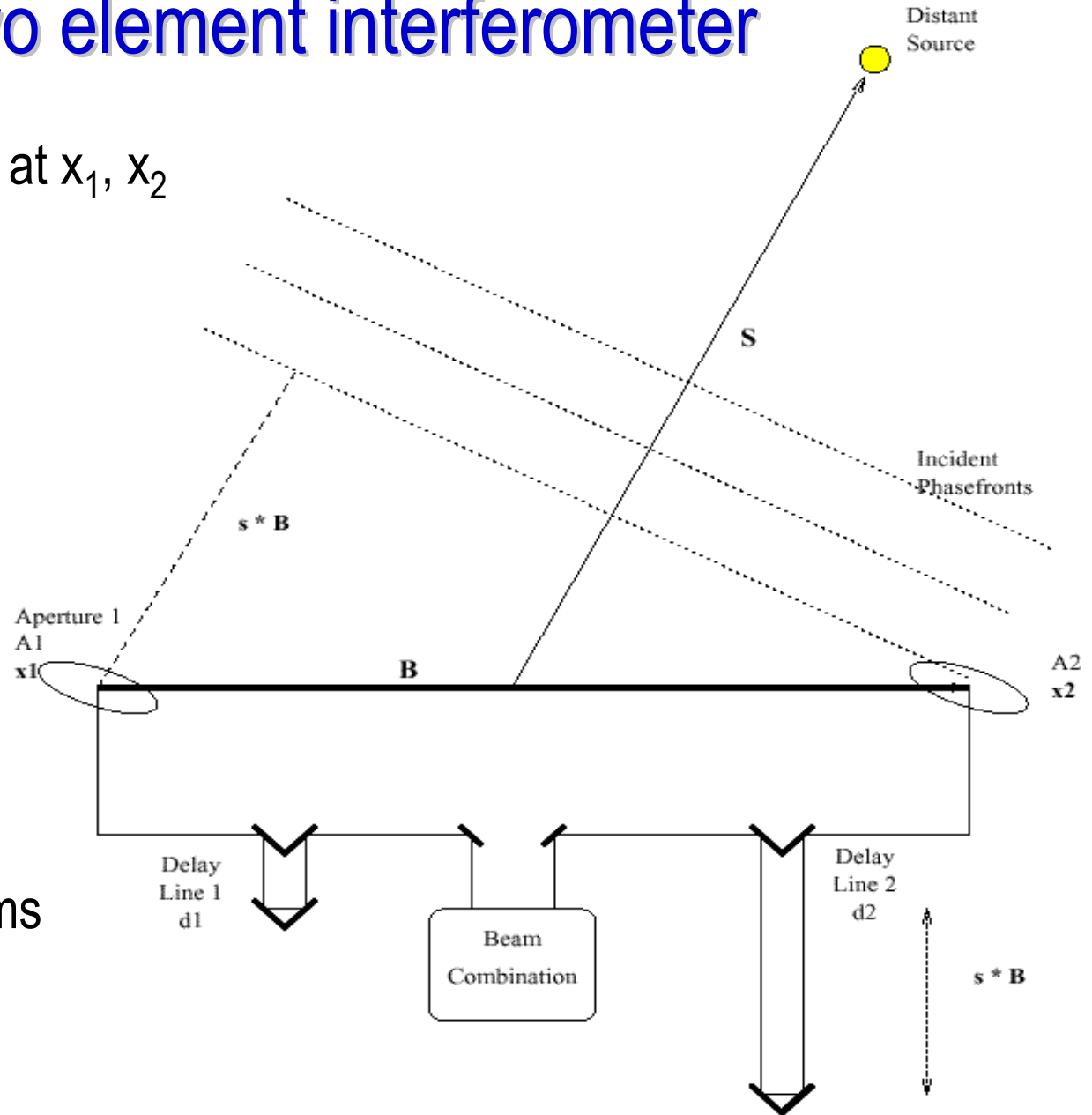
A two element interferometer

- Sampling of the radiation
- Compensation for the geometric delay
- Combination of the beams
- Detection of the resulting output



A two element interferometer

- Telescopes located at x_1, x_2
- Baseline $B = (x_1 - x_2)$
- Pointing direction is S
- Geometric delay is $\hat{s} \cdot B$, where $\hat{s} = S/|S|$
- Paths along two arms are d_1 and d_2



The output of a 2-element interferometer (i)

- The fields at two apertures can be written as:
 - $\psi_1 = A \exp (ik[\hat{s}.B + d_1]) \exp (-i\omega t)$ and $\psi_2 = A \exp (ik[d_2]) \exp (-i\omega t)$
- So the sum of the fields is:

$$\Psi = \psi_1 + \psi_2 = A \left[\exp (ik[\hat{s}.B + d_1]) + \exp (ik[d_2]) \right] \exp (-i\omega t)$$

- And hence the time averaged intensity, $\langle \Psi \Psi^* \rangle$, will be given by:

$$\begin{aligned} \langle \Psi \Psi^* \rangle &\propto \langle [\exp (ik[\hat{s}.B + d_1]) + \exp (ik[d_2])] \times [\exp (-ik[\hat{s}.B + d_1]) + \exp (-ik[d_2])] \rangle \\ &\propto 2 + 2 \cos (k [\hat{s}.B + d_1 - d_2]) \\ &\propto 2 + 2 \cos (kD) \end{aligned}$$

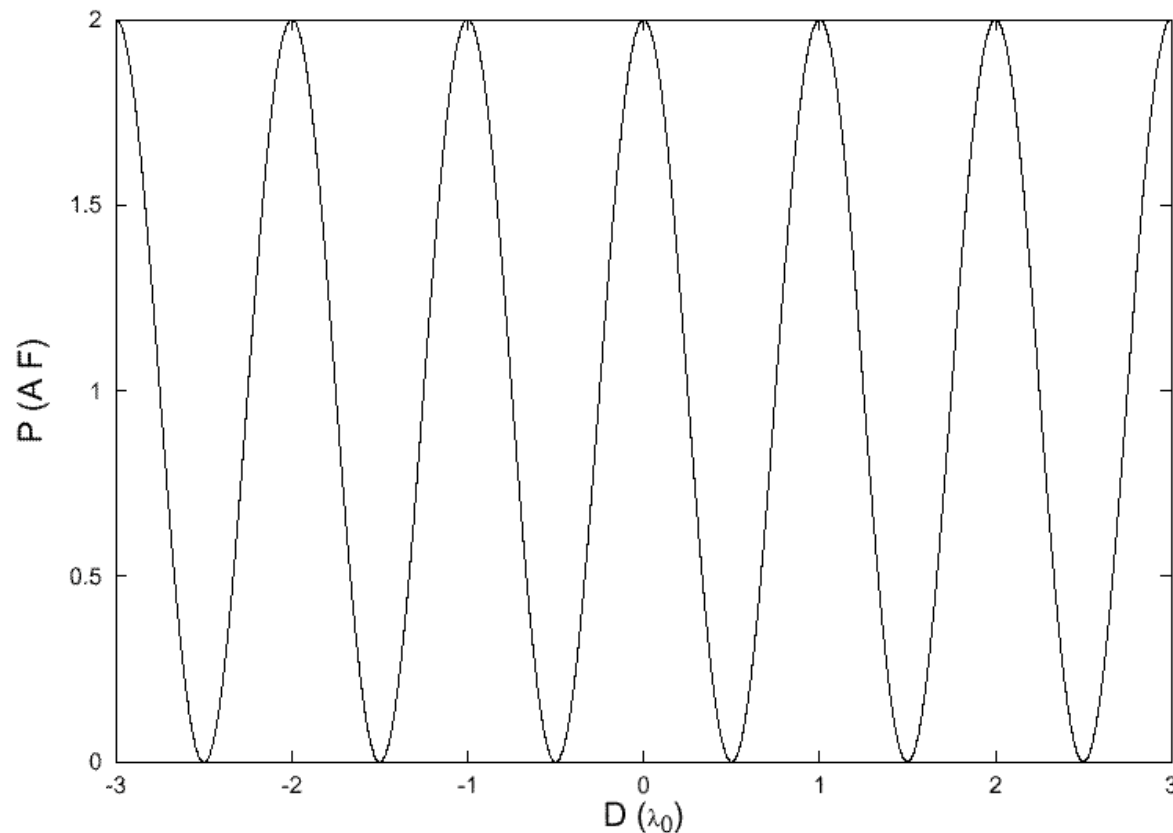
Note, here $D = [\hat{s}.B + d_1 - d_2]$.

This is a function of the path lengths, d_1 and d_2 , the pointing direction and the baseline.

The output of a 2-element interferometer (ii)

$$\begin{aligned} \text{Detected power, } P &= \langle \Psi \Psi^* \rangle \propto 2 + 2 \cos (k [\hat{s} \cdot \mathbf{B} + d_1 - d_2]) \\ &\propto 2 + 2 \cos (kD), \text{ where } D = [\hat{s} \cdot \mathbf{B} + d_1 - d_2] \end{aligned}$$

- The output varies co-sinusoidally with D .
- Adjacent fringe peaks are separated by $\Delta d_{1 \text{ or } 2} = \lambda$ or $\Delta \hat{s} = \lambda/B$.

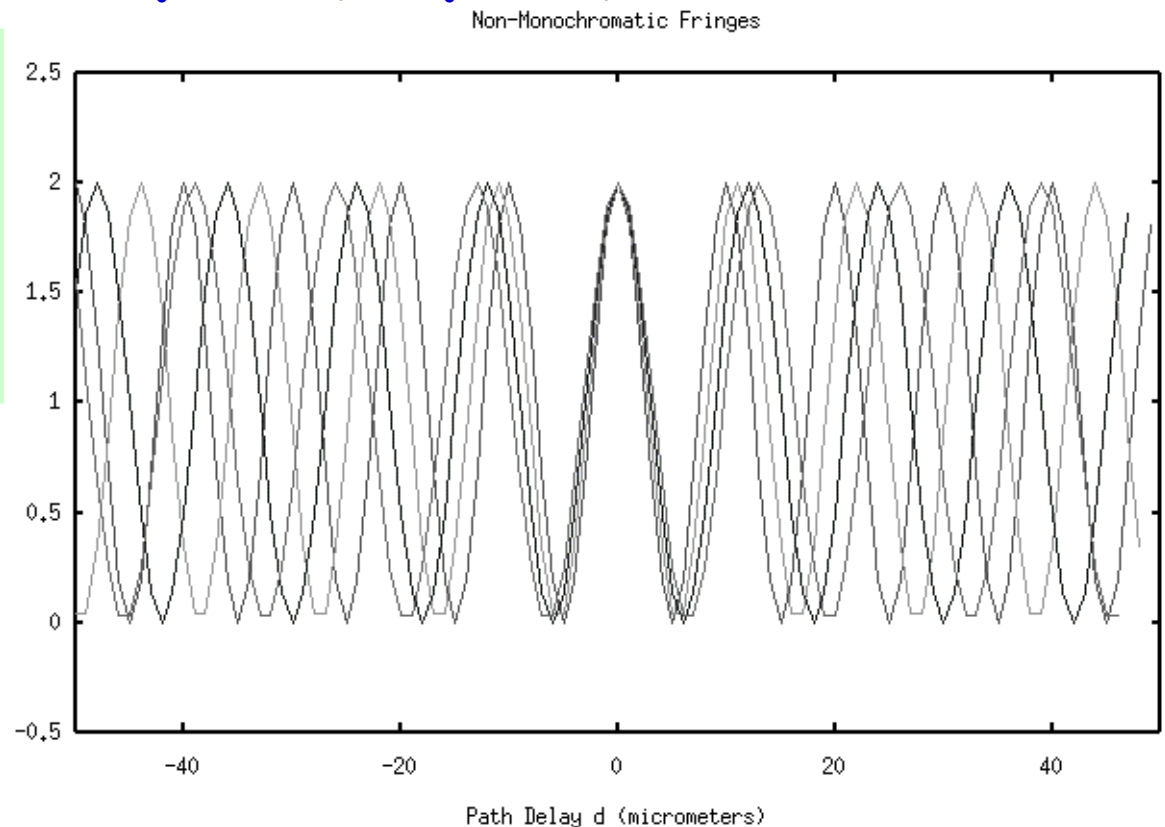


Extension to polychromatic light

- Simply integrate the previous result over a range of wavelengths:
 - E.g for a uniform bandpass of $\lambda_0 \pm \Delta\lambda/2$ (i.e. $\nu_0 \pm \Delta\nu/2$) we obtain

$$P \propto \int_{\lambda_0 - \Delta\lambda/2}^{\lambda_0 + \Delta\lambda/2} [2 + 2\cos(kD)] d\lambda$$

$$\propto \int_{\nu_0 - \Delta\nu/2}^{\nu_0 + \Delta\nu/2} 2[1 + \cos(2\pi\nu D/c)] d\nu$$



Extension to polychromatic light

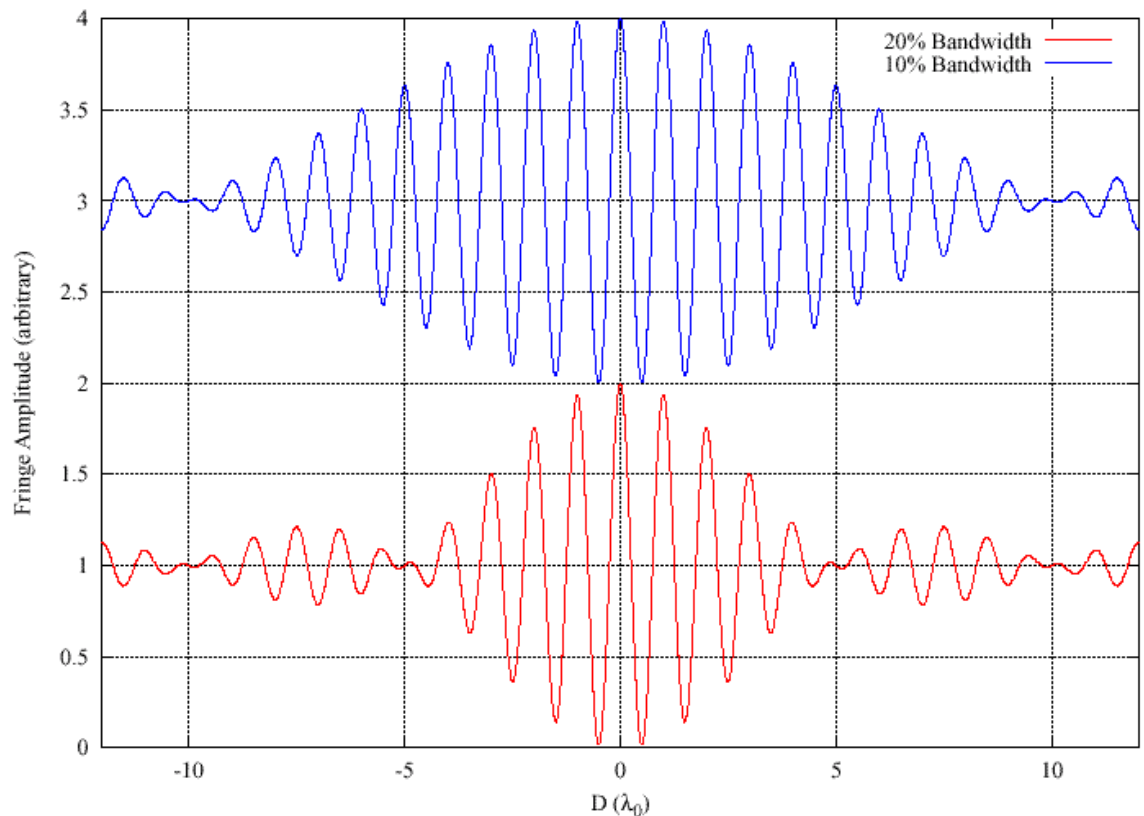
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$$P \propto \int_{\nu_0 - \Delta\nu/2}^{\nu_0 + \Delta\nu/2} [2 + 2 \cos(kD)] d\nu$$

$$= \int_{\nu_0 - \Delta\nu/2}^{\nu_0 + \Delta\nu/2} 2 [1 + \cos(2\pi\nu D / c)] d\nu$$

$$= \Delta\lambda \left[1 + \frac{\sin \pi D \Delta\lambda / \lambda_0^2}{\pi D \Delta\lambda / \lambda_0^2} \cos k_0 D \right]$$

$$= \Delta\lambda \left[1 + \frac{\sin \pi D / \Lambda_{coh}}{\pi D / \Lambda_{coh}} \cos k_0 D \right]$$



- NB The fringes are modulated with an envelope with a characteristic width equal to the coherence length, $\Lambda_{coh} = \lambda_0^2 / \Delta\lambda$.

Fringe parameters of interest

- From an interferometric point of view the key features of any interference fringes are their **modulation** and their **location** with respect to some reference point.

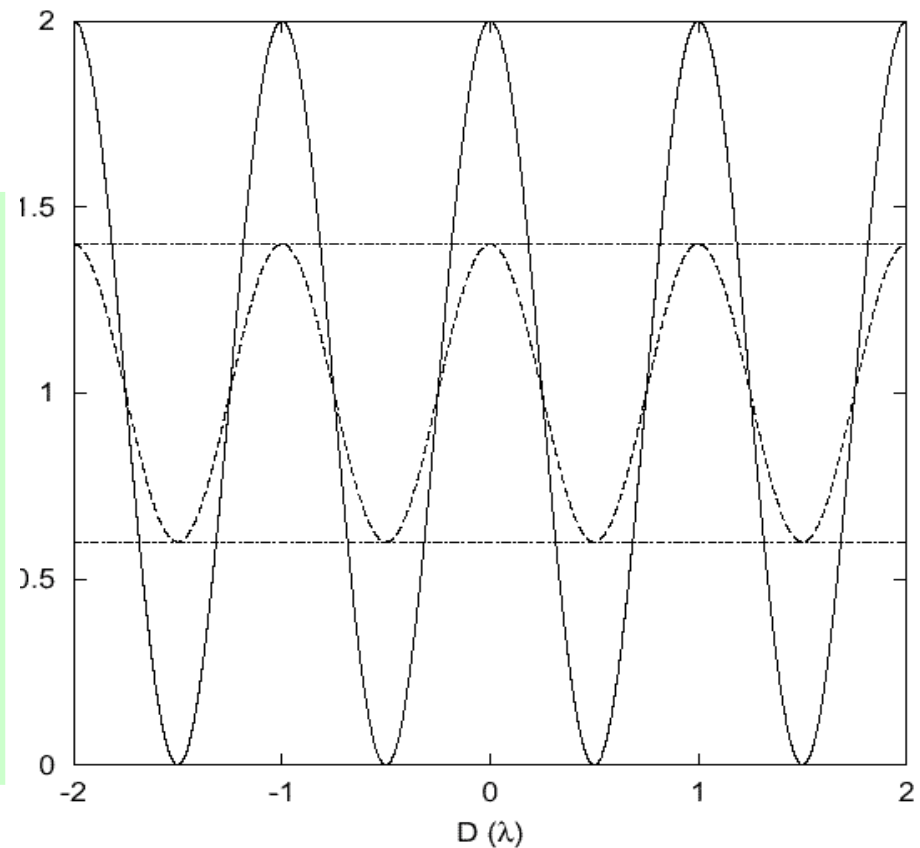
- In particular we can identify:

- The fringe **visibility**:

$$V = \frac{[I_{\max} - I_{\min}]}{[I_{\max} + I_{\min}]}$$

- The fringe **phase**:

- The location of the white-light fringe as measured from some reference (radians).



The essential physics

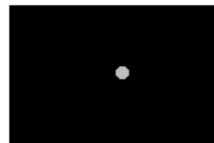


Binary object composed of two point sources

Can be considered as two individual sources

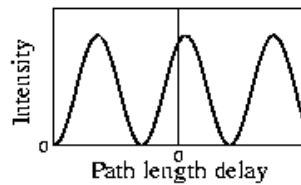
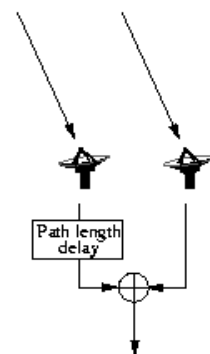
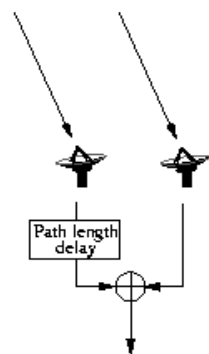


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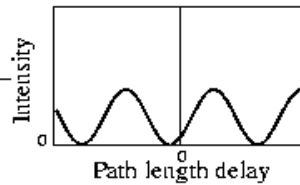
Bright source

Faint source



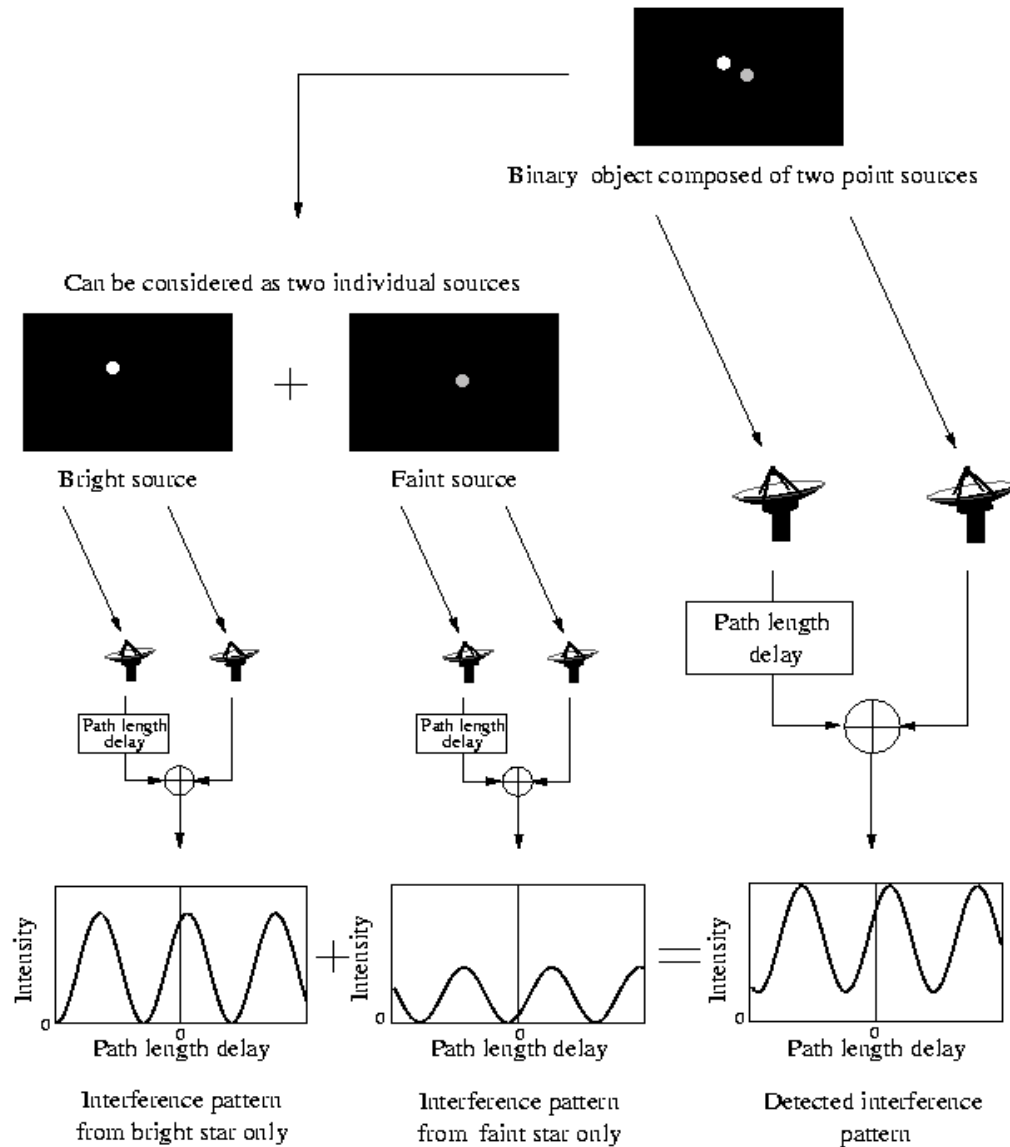
Interference pattern from bright star only

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Interference pattern from faint star only

The essential physics



- The resulting fringe pattern has a **modulation depth** that is reduced with respect to that from each source individually.
- The positions of the sources are encoded in the **fringe phase**.

Response to a distributed source

- Consider looking at an incoherent source whose brightness on the sky is described by $I(\hat{s})$. This can be written as $I(\hat{s}_0 + \Delta s)$, where \hat{s}_0 is the pointing direction, and Δs is a vector perpendicular to this.
- The detected power will be given by:

$$\begin{aligned} P(\hat{s}_0, B) &\propto \int I(\hat{s}) [1 + \cos kD] d\Omega \\ &\propto \int I(\hat{s}) [1 + \cos k(\hat{s} \cdot B + d_1 - d_2)] d\Omega \\ &\propto \int I(\hat{s}) [1 + \cos k([\hat{s}_0 + \Delta s] \cdot B + d_1 - d_2)] d\Omega \\ &\propto \int I(\hat{s}) [1 + \cos k(\hat{s}_0 \cdot B + \Delta s \cdot B + d_1 - d_2)] d\Omega \\ &\propto \int I(\Delta s) [1 + \cos k(\Delta s \cdot B)] d\Omega' \end{aligned}$$

The van Cittert-Zernike theorem (i)

- Consider now adding a small phase delay, δ , to one arm of the interferometer. The detected power will become:

$$\begin{aligned} P(\hat{s}_0, B, \delta) &\propto \int I(\Delta s) [1 + \cos k(\Delta s \cdot B + \delta)] d\Omega \\ &\propto \int I(\Delta s) d\Omega + \cos k\delta \cdot \int I(\Delta s) \cos k(\Delta s \cdot B) d\Omega \\ &\quad - \sin k\delta \cdot \int I(\Delta s) \sin k(\Delta s \cdot B) d\Omega \end{aligned}$$

- Introducing the complex visibility $V(k, B)$ we can write:

$$V(k, B) = \int I(\Delta s) \exp[-ik\Delta s \cdot B] d\Omega$$

so that:

$$P(\hat{s}_0, B, \delta) \propto \int I(\Delta s) d\Omega + \cos k\delta \operatorname{Re}[V] + \sin k\delta \operatorname{Im}[V]$$

$$P(\hat{s}_0, B, \delta) = I_{total} + \operatorname{Re}[V \exp[-ik\delta]]$$

The van Cittert-Zernike theorem (ii)

- Now assume $\hat{s}_0 = (0,0,1)$ and Δs is small and $\approx (\alpha, \beta, 0)$, with α and β angles measured in radians.

- This implies
$$V(k, B) = \int I(\alpha, \beta) \exp[-ik(\alpha B_x + \beta B_y)] d\alpha d\beta$$

- So that
$$V(u, v) = \int I(\alpha, \beta) \exp[-i2\pi(\alpha u + \beta v)] d\alpha d\beta$$

where $u (=B_x/\lambda)$ and $v (=B_y/\lambda)$ are spatial frequencies with units rad^{-1} .

- Since
$$P(\hat{s}_0, B, \delta) = I_{total} + \text{Re}[V \exp[-ik\delta]]$$

what this means is that the interferometer response measures the Fourier transform of the sky brightness distribution.

This is the van Cittert-Zernike theorem.

Simple sources (i)

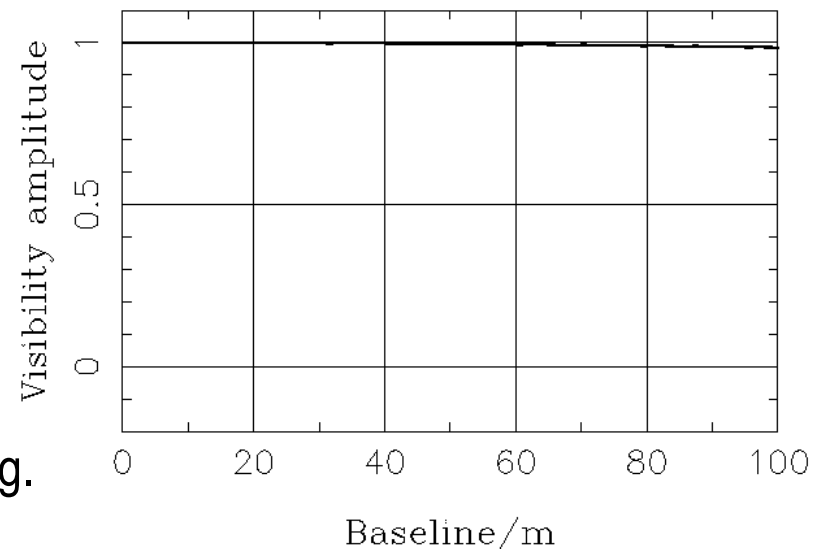
$$V(u) = \int I(l) e^{-i2\pi(u)l} dl / \int I(l) dl$$

- Point source of strength A_1 and located at angle l_1 relative to the optical axis.

$$\begin{aligned} V(u) &= \int A_1 \delta(l-l_1) e^{-i2\pi(u)l} dl / \int A_1 \delta(l-l_1) dl \\ &= e^{-i2\pi(u)l_1} \end{aligned}$$

0.5 mas diameter uniform disk at 2.2 microns

- The **visibility amplitude** is unity $\forall u$.
- The **visibility phase** varies linearly with u ($= B/\lambda$).
- Sources such as this are easy to observe, but of little interest if you've built an interferometer for high-angular resolution imaging.



Simple sources (ii)

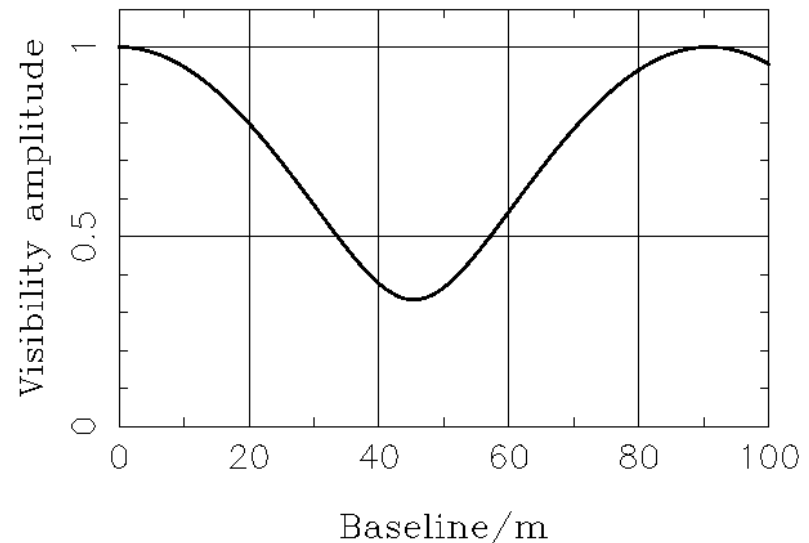
$$V(u) = \int I(l) e^{-i2\pi(u)l} dl / \int I(l) dl$$

- A double source comprising point sources of strength A_1 and A_2 located at angles 0 and l_2 relative to the optical axis.

$$\begin{aligned} V(u) &= \int [A_1\delta(l) + A_2\delta(l-l_2)] e^{-i2\pi(u)l} dl / \int [A_1\delta(l) + A_2\delta(l-l_2)] dl \\ &= [A_1 + A_2 e^{-i2\pi(u)l_2}] / [A_1 + A_2] \end{aligned}$$

5 mas binary with 2:1 flux ratio at 2.2 microns

- The visibility amplitude and phase **oscillate** as functions of u .
- To identify this as a binary, baselines from $0 \rightarrow \lambda/l_2$ are required.
- If the ratio of component fluxes is large the modulation of the visibility becomes increasingly difficult to measure.



Simple sources (iii)

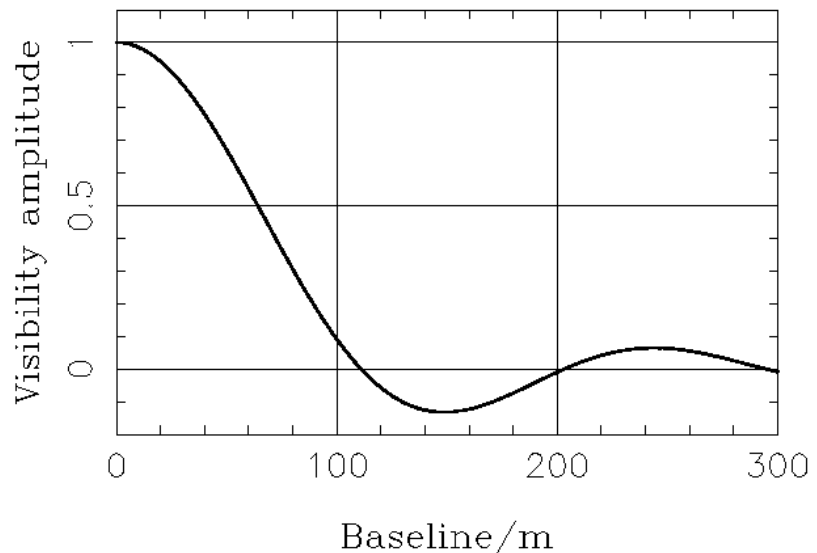
$$V(u) = \int I(l) e^{-i2\pi(ul)} dl / \int I(l) dl$$

- A uniform on-axis disc source of diameter θ .

$$\begin{aligned} V(u_r) &\propto \int_0^{\theta/2} \rho J_0(2\pi\rho u_r) d\rho \\ &= 2J_1(\pi\theta u_r) / (\pi\theta u_r) \end{aligned}$$

- To identify this as a disc requires baselines from $0 \rightarrow \lambda/\theta$ at least.
- The visibility amplitude falls rapidly as u_r increases.
- Information on scales smaller than the disc diameter correspond to values of u_r where $V \ll 1$, and is hence difficult to measure.

5 mas diameter uniform disk at 2.2 microns



Review of interferometric imaging

- The visibility function, $V(u, v) = V(B_x/\lambda, B_y/\lambda)$, is the Fourier transform of the source brightness distribution.
- So measure V for as many values of B as possible & perform an inverse FT.

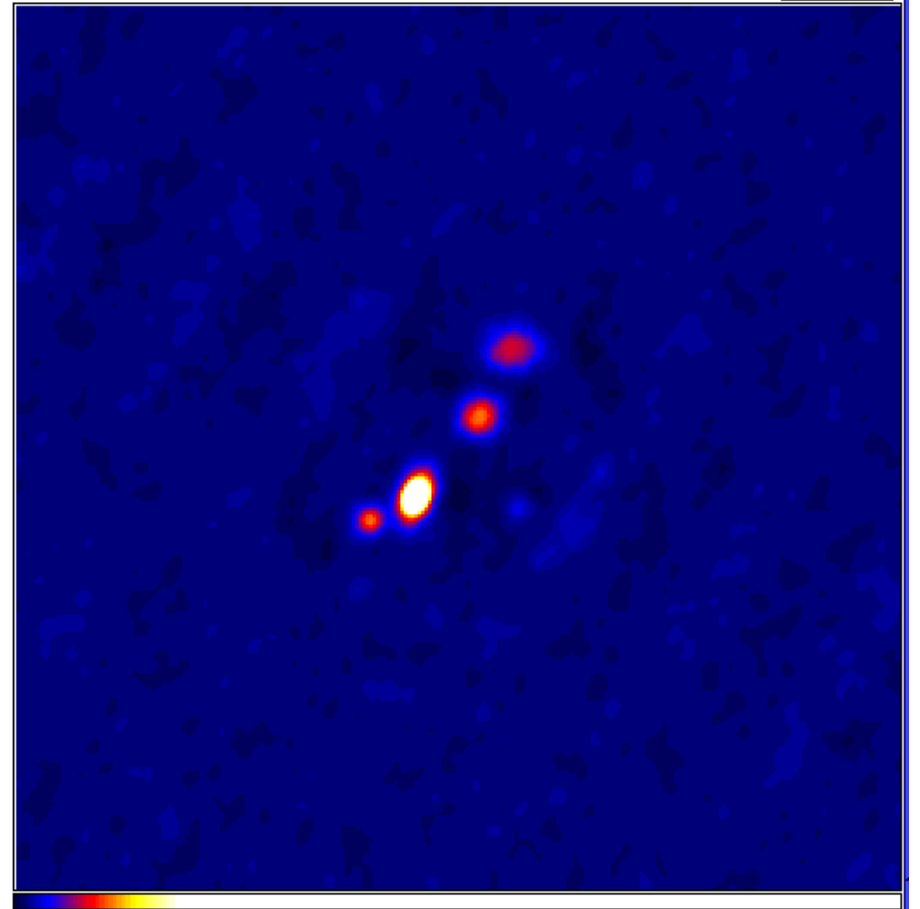
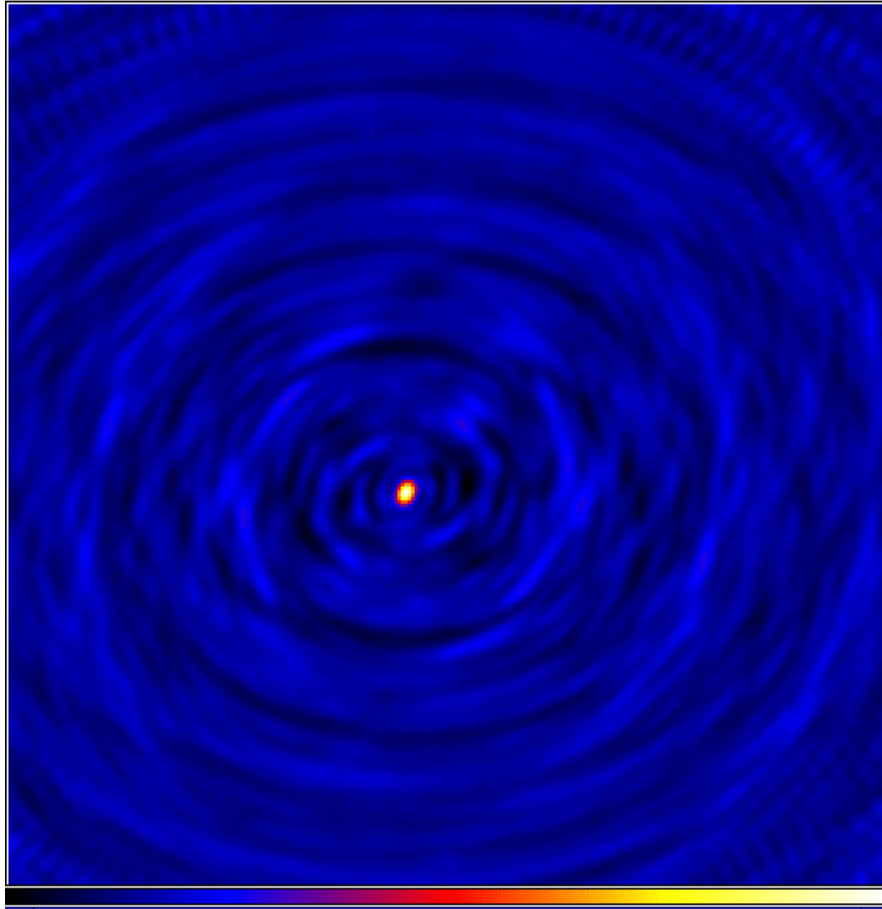
$$I_{\text{norm}}(l, m) = \iint V(u, v) e^{+i2\pi(ul + vm)} du dv$$

- Since what we measure is a **sampled** version of $V(u, v)$, what we actually recover is the so-called “**dirty map**”:

$$\begin{aligned} I_{\text{dirty}}(l, m) &= \iint S(u, v) V(u, v) e^{+i2\pi(ul + vm)} du dv \\ &= B_{\text{dirty}}(l, m) * I_{\text{norm}}(l, m), \end{aligned}$$

where $B_{\text{dirty}}(l, m)$ is the Fourier transform of the sampling distribution, or **dirty-beam**.

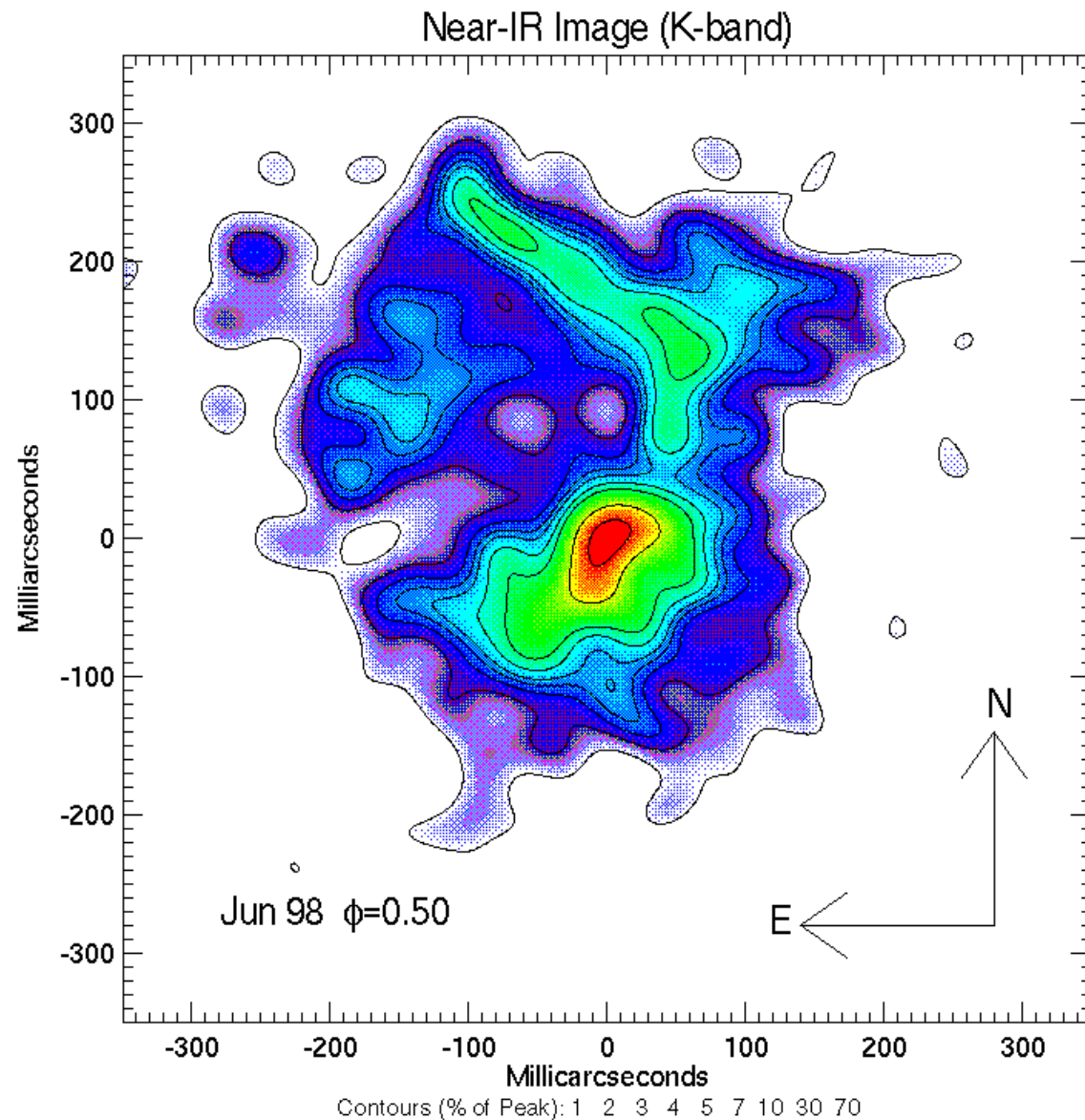
Dirty (and corrected) interferometric images



- Correcting an interferometric map for the Fourier plane sampling function is known as **deconvolution** (CLEAN, MEM, WIPE).

A real astronomical example

K-band image of
IRC+10216.
Image courtesy of
Peter Tuthill and
John Monnier.



Summary

- Interferometers measure fringes.
- The fringe modulation and phase are the quantities of interest.
- These measure the amplitude and phase of the FT of the source brightness distribution (the visibility function).
- Any given interferometer baseline responds to a single spatial frequency in the source brightness distribution.
- Multiple baselines are obligatory to build up an image.
- Once many visibility measurements are made, an inverse FT delivers a representation of the source that may (or may not) be useful!